

# PC910H0NSZ

## High Speed Response , High CMR OPIC Photocoupler

### ■ Features

1. High resistance to noise due to high common rejection voltage (CMR:MIN. 10kV/ $\mu$ s)
2. High speed response ( $t_{PHL}$ ,  $t_{PLH}$  MAX. 75ns)
3. Isolation voltage between input and output (Viso (rms):2.5kV)
4. 8-pin DIP package

### ■ Applications

1. Programmable controllers
2. Inverters

### ■ Absolute Maximum Ratings (Ta=25°C)

	Parameter	Symbol	Rating	Unit
Input	*1 Forward current	$I_F$	20	mA
	Reverse voltage	$V_R$	5	V
	Power dissipation	P	40	mW
Output	Supply voltage	$V_{CC}$	7	V
	*2 Enable voltage	$V_E$	5.5	V
	High level output voltage	$V_{OH}$	7	V
	Low level output current	$I_{OL}$	50	mA
	*3 Collector power dissipation	$P_C$	85	mW
	*4 Isolation voltage	$V_{iso (rms)}$	2.5	kV
	Operating temperature	$T_{opr}$	-40 to +85	°C
	Storage temperature	$T_{stg}$	-55 to +125	°C
	*5 Soldering temperature	$T_{sol}$	260	°C

\*1 Refer to Fig.5

\*2 Shall not exceed 500mV from supply voltage ( $V_{CC}$ )

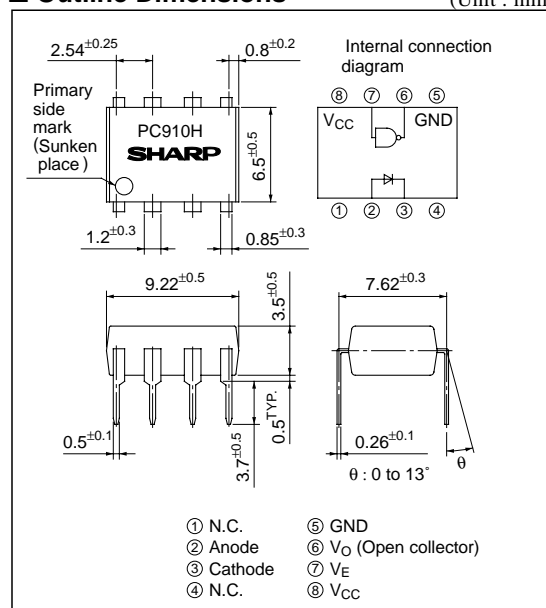
\*3 Refer to Fig.7

\*4 40 to 60%RH, AC for 1 min

\*5 For 10 s

### ■ Outline Dimensions

(Unit : mm)



\* "OPIC"(Optical IC) is a trademark of the SHARP Corporation. An OPIC consists of a light-detecting element and signal-processing circuit integrated onto a single chip.

## ■ Electro-optical Characteristics \*6

(Unless otherwise specified, Ta=−40 to 85°C)

Parameter		Symbol	Conditions	MIN.	TYP.	MAX.	Unit	
Input	Forward voltage	V <sub>F</sub>	Ta=25°C, I <sub>F</sub> =10mA	—	1.6	1.9	V	
	Reverse current	I <sub>R</sub>	Ta=25°C, V <sub>R</sub> =5V	—	—	10	μA	
	Terminal capacitance	C <sub>t</sub>	Ta=25°C, V <sub>F</sub> =0V, f=1MHz	—	60	150	pF	
Output	High level output current	I <sub>OH</sub>	V <sub>CC</sub> =V <sub>O</sub> =5.5V, V <sub>E</sub> =2.0V, I <sub>F</sub> =250μA	—	0.02	100	μA	
	Low level output voltage	V <sub>OL</sub>	V <sub>CC</sub> =5.5V, V <sub>E</sub> =2.0V, I <sub>F</sub> =5mA, I <sub>OL</sub> =13mA	—	0.4	0.6	V	
	High level enable current	I <sub>EH</sub>	V <sub>CC</sub> =5.5V, V <sub>E</sub> =2.0V	—	−0.5	−1.6	mA	
	Low level enable current	I <sub>EL</sub>	V <sub>CC</sub> =5.5V, V <sub>E</sub> =0.5V	—	−0.7	−1.6	mA	
	High level supply current	I <sub>CCH</sub>	V <sub>CC</sub> =5.5V, I <sub>F</sub> =0mA, V <sub>E</sub> =2V	—	5	10	mA	
			V <sub>CC</sub> =5.5V, I <sub>F</sub> =0mA, V <sub>E</sub> =0.5V	—	5	—	mA	
	Low level supply current	I <sub>CCL</sub>	V <sub>CC</sub> =5.5V, I <sub>F</sub> =10mA, V <sub>E</sub> =2V	—	7	13	mA	
			V <sub>CC</sub> =5.5V, I <sub>F</sub> =10mA, V <sub>E</sub> =0.5V	—	5.5	—	mA	
Transfer characteristics	"High→Low" threshold input current	I <sub>FHL</sub>	V <sub>CC</sub> =5V, V <sub>E</sub> =2.0V V <sub>O</sub> =0.8V, R <sub>L</sub> =350Ω	—	2.5	5	mA	
	Isolation resistance	R <sub>ISO</sub>	Ta=25°C, DC=500V, 40 to 60% RH	5×10 <sup>10</sup>	1×10 <sup>11</sup>	—	Ω	
	Floating capacitance	C <sub>f</sub>	Ta=25°C, V=0V, f=1MHz	—	0.6	5	pF	
	Response time	"High→Low" propagation delay time	t <sub>pHL</sub>	Ta=25°C, V <sub>CC</sub> =5V R <sub>L</sub> =350Ω, C <sub>L</sub> =15pF I <sub>F</sub> =7.5mA Fig.3	25	48	75	ns
		"Low→High" propagation delay time	t <sub>pLH</sub>		25	50	75	ns
		Rise time	t <sub>r</sub>		—	10	—	ns
		Fall time	t <sub>f</sub>		—	20	—	ns
		*7 Pulse width distortion	t <sub>w</sub>		—	—	35	ns
		"High→Low" enable propagation delay time	t <sub>EH</sub>	Ta=25°C, V <sub>CC</sub> =5V R <sub>L</sub> =350Ω, C <sub>L</sub> =15pF I <sub>F</sub> =7.5mA, V <sub>EH</sub> =3V V <sub>EL</sub> =0.5V Fig.4	—	15	—	ns
		"Low→High" enable propagation delay time	t <sub>EL</sub>		—	10	—	ns
	CMR	Instantaneous common mode rejection voltage "Output : High level"	CM <sub>H</sub>	Ta=25°C, V <sub>CC</sub> =5V V <sub>CM</sub> (P-P)=1kV, R <sub>L</sub> =350Ω I <sub>F</sub> =0mA, V <sub>O</sub> (Min)=2V Fig.5	10	20	—	kV/μs
		Instantaneous common mode rejection voltage "Output : Low level"	CM <sub>L</sub>	Ta=25°C, V <sub>CC</sub> =5V V <sub>CM</sub> (P-P)=1kV, R <sub>L</sub> =350Ω I <sub>F</sub> =5mA, V <sub>O</sub> (Max)=0.8V Fig.5	−10	−20	—	kV/μs

\*6 When measuring output and transfer characteristics, connect a by-pass capacitor (0.01μF or more) between  $V_{CC}$  ⑧ and GND ⑤ near the PC910H0NSZ\*7 \*5 Pulse width distortion  $\Delta tw = |t_{PHL} - t_{PLH}|$ All typical values: at Ta=25°C,  $V_{CC}=5\text{V}$ 

Fig.1 Block Diagram

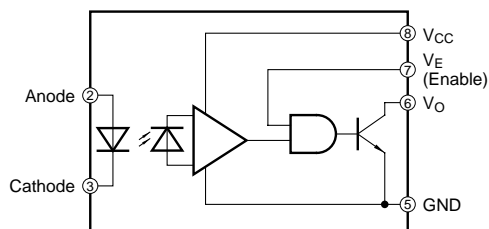
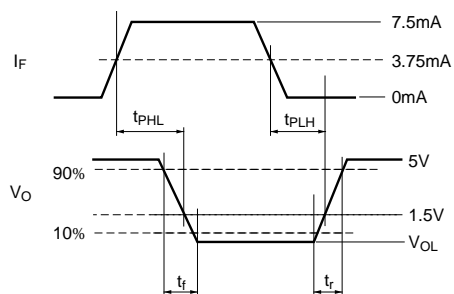
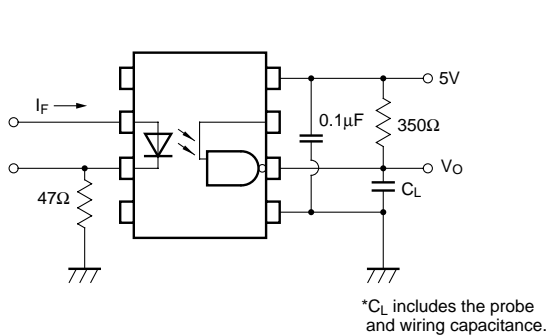
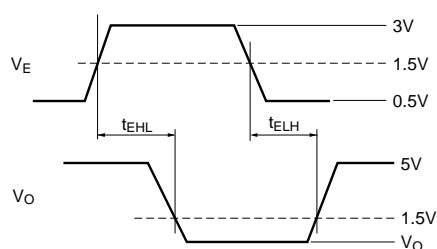
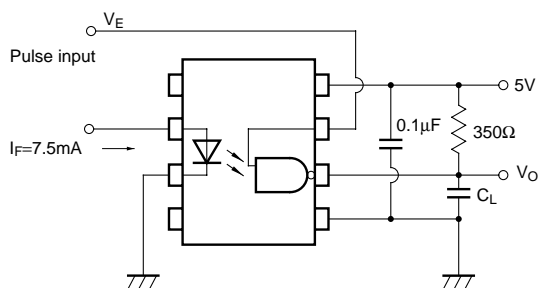
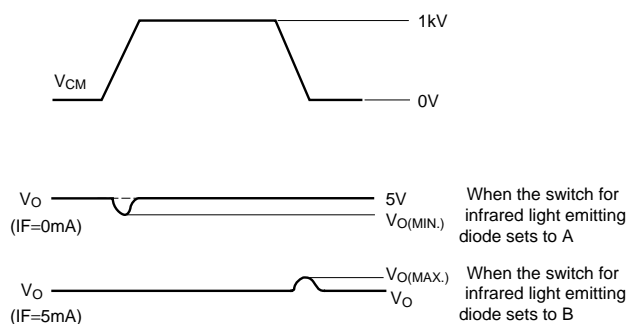
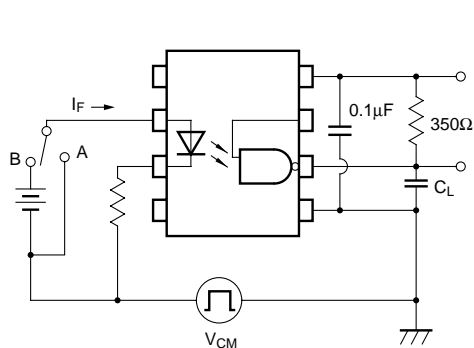


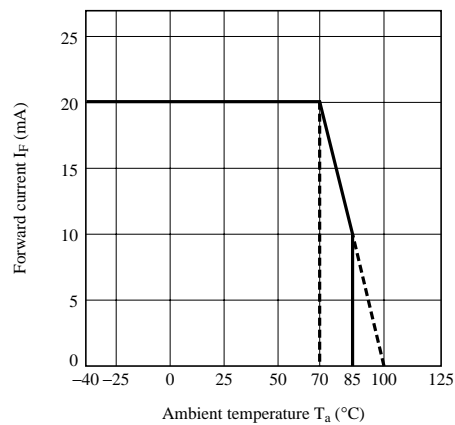
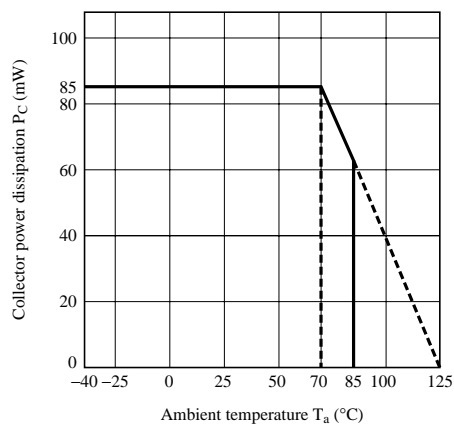
Fig.2 Truth Table

Input	Enable	Output
H	H	L
L	H	H
H	L	H
L	L	H

L : Logic (0)

H : Logic (1)

Fig.3 Test Circuit for  $t_{pHL}$ ,  $t_{pLH}$ ,  $t_r$  and  $t_f$ Fig.4 Test Circuit for  $t_{EHL}$  and  $t_{ELH}$ Fig.5 Test Circuit for  $CM_H$  and  $CM_L$ 

**Fig.6 Forward Current vs. Ambient Temperature****Fig.7 Collector Power Dissipation vs. Ambient Temperature**

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